

(19)



JAPANESE PATENT OFFICE

10-98-29338

PATENT ABSTRACTS OF JAPAN

(11) Publication number: 63033665 A

(43) Date of publication of application: 13.02.88

(51) Int. Cl. G01R 27/02
H05K 3/46

(21) Application number: 61176923

(22) Date of filing: 28.07.86

(71) Applicant: MATSUSHITA ELECTRIC IND CO LTD

(72) Inventor: URAOKA YUKIHARU

(54) CONTACT RESISTANCE MEASURING PATTERN

(57) Abstract

PURPOSE: To measure a contact chain having resistance optimum to a measuring apparatus regardless of the kind of a layer to be contacted and the magnitude of contact resistance, by using a measuring pattern composed of the combination constitution of three kinds of patterns.

CONSTITUTION: A contact resistance measuring pattern is formed of a first pattern 10, a second pattern 200 and a third pattern 300. The first pattern 100 is constituted by contacting two wiring bodies 10, 11 through a wiring layer 20 composed of a diffusion layer and has pads 0W5. The second pattern 200 is constituted by connecting one wiring body 12 by a wiring body 21 composed of a diffusion layer and has pads 6, 7. The third pattern 300 is present at the middle between the first and second patterns and constituted of wiring bodies 13W15, 22W24 and pads 8, 9. In measuring contact resistance or a contact chain, a current is made to flow from each pad and potential difference between pads is measured.

COPYRIGHT: (C)1988,JPO&Japio

